					IAP	5 Rec'd	PCT/PTH <sup>h</sup>	28 Sep on	
Form PTO-1449 U.S. Department of Commodified) Patent and Trademark					Attorney's Docket No 28953.2004		Application No.		
Information Disclosure Statement by Applicant					Applicant Makoto IWAT et al				
(Use several sheets if necessary)					Filing Date 11/0	8/2006	Group Art Uni	t	
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Examiner Signature	Date Considered				
/Felisa Hiteshew/	04/11/2008				
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